

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICESUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)ATTY. DOCKET NO.
671096.403USPCAPPLICATION NO.
10/518,651APPLICANTS
Andrei NIKULINFILING DATE
July 18, 2005GROUP ART UNIT
2882

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AI					
	AJ					
	AK					
	AL					
	AM					

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

CT	AN	Siu, Karen, et al., "X-ray phase retrieval in high-resolution refraction data from amorphous materials," <i>Applied Physics Letters</i> , 79(13):2112-2114, September 24, 2001.
↓	AO	Siu, Karen, et al., "Phase Retrieval X-ray Diffractometry (PRXRD): Refraction/Small angle scattering data applications," <i>Proc. SPIE, Advances in X-Ray Optics</i> , 4145: 157-167, 2001.; Abstract (1 page).
	AP	Siu, Karen, et al., "An application of phase retrieval x-ray diffractometry to refraction/small-angle scattering data," <i>J. Phys. D: Appl. Phys.</i> , 34: 2912-2917, 2001.

EXAMINER Courtney Thomas

DATE CONSIDERED 05.28.07

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).